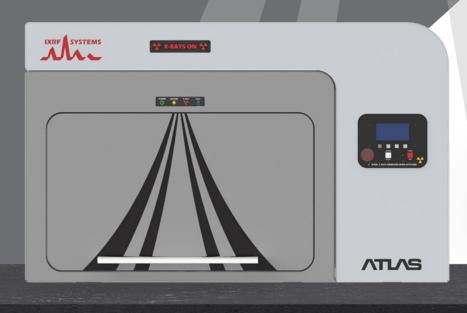


## UNPARALLELED MICRO-XRF PERFORMANCE



# ATLAS: RAISING THE STANDARD FOR MICRO-XRF





The ATLAS Micro-XRF is the very latest in small spot spectrometer engineering. Made with a myriad of markets in mind, it truly is the most versatile Micro-XRF instrument. Solids, liquids, particles, powders; small and large, as well as rough or polished, nearly any sample can be accommodated.

Where other micro-xrf products are deficient, ATLAS was designed to excel. ATLAS leads the industry in virtually every major specification category from the largest chamber and detector active area size, to the longest mapping travel and smallest micro-spot.

Hardware specifications are only half of the ATLAS Advantage™. The ATLAS software platform is simply unsurpassed. The functional, flexible, and feature-rich software suite guarantees unprecedented production. ATLAS is not just an instrument, it is the Micro-XRF roadmap of the future.

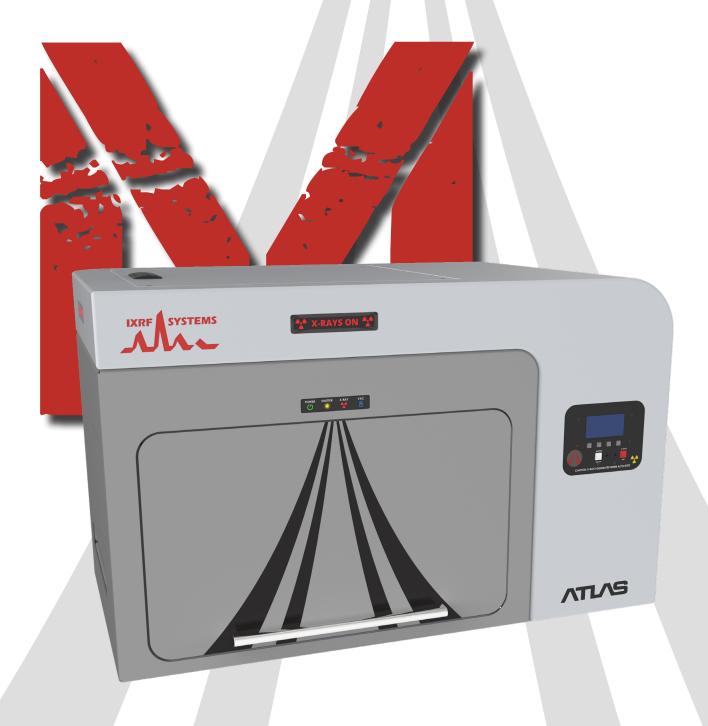




The ATLAS™ X Micro-XRF spectrometer (µXRF) from IXRF Systems introduces a new world of x-ray mapping and automation. The ATLAS™ X boasts the largest chamber volume and SDD detection area (150mm²) well as the smallest spot size (5µm) available on the market. Additionally, the ATLAS™ X is complimented by the most comprehensive software suite including multi-point analysis, unattended automation, in-depth feature/image analysis, unprecedented mapping and reporting features, and much more. Models may be operated under air or vacuum as well as Helium flush for liquids and light element analysis.

## **PRODUCT FEATURES**

- 1) Spot Size down to 5 microns with anti-halo optic
- 2 SDD Detector Active Area up to 150mm<sup>2</sup>
- 3 Larger Chamber Volume
- 4 50kv/50 watt tube
- 5 Multipoint/Multi-Area Automation & Mapping
- 6 Air, Vacuum, Helium for Solids, liquids, and powders



The ATLAS™ Micro-XRF spectrometer (µXRF) from IXRF Systems introduces a new world of x-ray mapping and automation. The ATLAS™ boasts the largest chamber volume and detection area (150mm²) as well as the smallest spot size (5µm) available on the market. Additionally, the ATLAS™ is complimented by the most comprehensive software suite including multi-point analysis, unattended automation, in-depth feature/image analysis, unprecedented mapping and reporting features, and much more. Instruments may be operated under air or vacuum as well as Helium flush for liquids and light element analysis.

## **PRODUCT FEATURES**

- 1) Spot Size down to 5 microns with anti-halo optic
- 2 SDD Detector Active Area up to 150mm<sup>2</sup>
- (3) Larger Chamber Volume
- 4 50kv/50 watt tube
- 5 Multipoint/Multi-Area Automation & Mapping
- 6 Air, Vacuum, Helium for Solids, liquids, and powders



#### Excitation

- Spot size ≥5µm with polycapillary optics
- 50kV/50W/1mA Rh target (others available) x-ray tube
- Filter wheel with up to 8 filters positioned before the focusing optic
- Optional use of two x-ray tubes for different element ranges, targets, and spot sizes



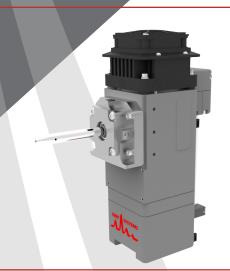


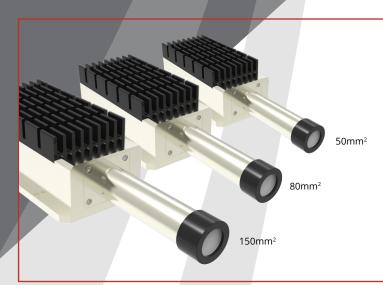


Hottest Tube



Most Filters





#### **Detectors**

- 50mm<sup>2</sup> to 150mm<sup>2</sup> for increased speed and reduced acquisition times
- ≤130-145eV resolution



Largest Active Area

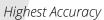
#### **Stages**

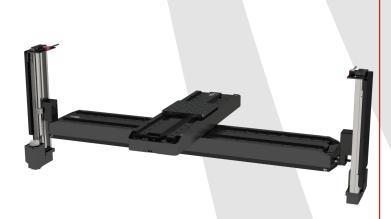
- Motorized XYZ
- Speeds up to 300mm/s (Map Acquistions ≤ 1ms/pixel)
- Accuracy less than 1µm



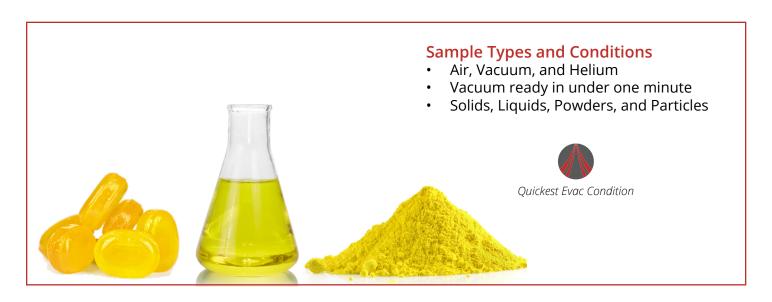
Fastest Stage







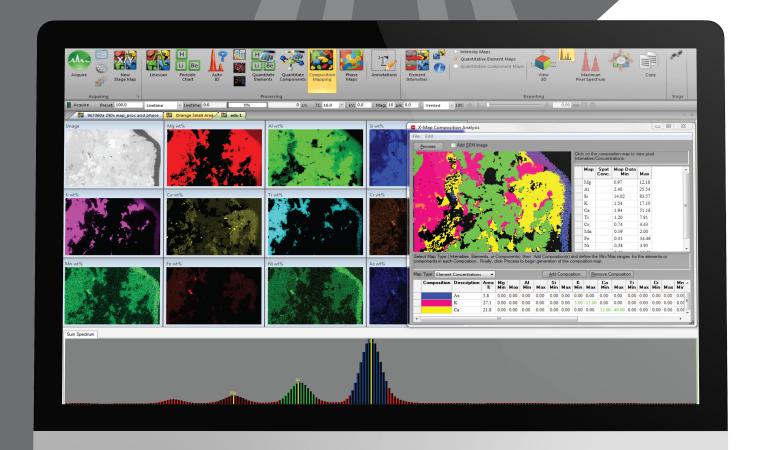












### **Spectral Collection & Quantitation**

- One-click acquisition and automatic peak identification
- Customizable identification, labeling, processing, and quantification
- Scrolling periodic chart
- Drag and drop overlay
- Automatic overlap correction, sum/ escape peak removal, background correction, and linear/non-linear deconvolution
- Fundamental Parameters (FP) and Quantitative Match
- Material classification databasing

## **Imaging**

- Multi-Point automated analysis directly from image
- Morphological processing for rapid feature size measurements
- Image stitching and montage
- Segmentation and feature segregation



## **Mapping and Linescans**

- Simultaneous acquisition of 35 elements
- 4096 x 4096 maximum map resolution (4096 linescan resolution)
- Stored spectral data for every pixel
- Live spectrum display during acquisition
- Single or multiple map acquisition from image; overview or spot camera
- Map stitching and montage
- Extract spectra from map: point, area, freehand
- Create linescan from map
- Mouse-over view intensities and concentrations
- Phase Analysis
- Multi-compositional map display of element and compound ranges
- Overlay linescans on image

## **Specialty and Automation**

- Multilayer thin film and coatings analysis up to 10 layers
- ASTM E2926-13 Glass Analysis
- Track, store, and recall all stage locations and images



Custom Software Design by Request



Multi-Point Acquisition



LineScans



RoboStage



Particle Analysis & Morphology



Component Calculator



Multi-Compositional Mapping



**Phase Analysis** 



Spectral Acquisition



Thin Film



Stitching & Montage



View Intensities/ Concentrations



Custom Reporting & Templates



O Maximum Pixel<sup>l</sup> Spectrum



m Pixel Segmentation





ATLAS X TECHNICAL SPECIFICATIONS		
Sample Types	Solids, Liquids, Particles, Powders	
	37x26x14in (950x650x365mm)	
Sample Chamber Size	37820814111 (9308030830311111)	
Measurement Media	Air, Vacuum, He	
<b>Excitation Source</b> Primary Secondary	50W / 50kV / 1mA 4W-12W / 40kV-60kV / 0.4mA-1mA	
Excitation Parameters Target Materials Tube Spot Size Filters	Polycapillary or Aperture Collimation Rh (others available) 50kV, 50W, 1mA (optional 2nd tube) ≥5-1000µm Up to 8	
Geometry	Top-down Beam (Perpendicular)	
<b>Detector (s)</b> Resolution Active Area	SDD (Si-Pin upon request) 130-145eV 50-150mm <sup>2</sup>	
Stage	Motorized X,Y,Z (available) Up to 600x300mm ranges available	
Sample Travel Total Mapping Map Scan Speed Sample Speed	600x300x150mm 400x300mm 1-3ms/pixel up to 300mm/second	
Sample View	Three Sample Positioning and Analysis Cameras	
Instrument Control	PC; Windows 10 Complete control of parameters, filters, cameras, optical microscopes, sample illumination and positioning, and measurement media	
Power	100-240 V, 50/60 Hz	
Certifications	CE, RoHS, Radiation	
Element Range	Na-U	
Dimensions	67x31x64in (1690x787x1630mm)	
Quality and Safety	CE certified RoHS, Radiation < 1 μSv/h	



ATLAS M TECHNICAL SPECIFICATIONS	
Sample Types	Solids, Liquids, Particles, Powders
Sample Chamber Size	20x18x10in. (508x457x254mm)
Measurement Media	Air, Vacuum, He
Excitation Source Primary Secondary	50W / 50kV / 1mA 4W-12W / 40kV-60kV / 0.4mA-1mA
Excitation Parameters Target Materials Tube Spot Size Filters	Polycapillary or Aperture Collimation Rh (others available) 50kV, 50W, 1mA (optional 2nd tube) ≥5-1000µm Up to 8
Geometry	Top-down Beam (Perpendicular)
<b>Detector (s)</b> Resolution Active Area	SDD (Si-Pin upon request) 130-145eV 50-150mm <sup>2</sup>
Stage	Motorized X,Y,Z (available) 25x25mm up to 320x320mm ranges available
Sample Travel Total Mapping Map Scan Speed Sample Speed	320x320x120mm 220x200mm 1-3ms/pixel up to 300mm/second
Sample View	Three Sample Positioning and Analysis Cameras
Instrument Control	PC; Windows 10 Complete control of parameters, filters, cameras, optical microscopes, sample illumination and positioning, and measurement media
Power	100-240 V, 50/60 Hz
Certifications	CE, RoHS, Radiation
Element Range	Na-U
Dimensions	35x22x22in (890x560x560mm)
Quality and Safety	CE certified RoHS, Radiation < 1 μSv/h





10421 Old Manchaca Rd., Suite 620 Austin, TX 78748 Telephone: 512.386.6100 www.ixrfsystems.com